| Commercial | Package <br> Number | Package Description |
| :--- | :--- | :--- |
| 74F352PC | N16E | 16 Lead (0.300" Wide) Molded Dual-in-Line |
| 74F352SJ (Note 1) | M16D | 16 Lead ( $0.300^{\prime \prime}$ Wide) Molded Small Outline, JEDEC |

Note 1: Devices also available in $13^{\prime \prime}$ reel. Use suffix $=$ SJX

Connection Diagram
Pin Assignment for DIP and SOIC


TL/F/9519-1

## Features

- Inverted version of 'F153
- Separate enables for each multiplexer
- Input clamp diode limits high speed termination effects section. It can select two bits of data from four sources. The
two buffered outputs present data in the inverted (complementary) form. The 'F352 is the functional equivalent of the 'F153 except with inverted outputs.



## Unit Loading/Fan Out

| Pin Names | Description | 74F |  |
| :---: | :---: | :---: | :---: |
|  |  | U.L. <br> HIGH/LOW | Input $\mathrm{I}_{\mathrm{IH}} / \mathrm{I}_{\mathrm{IL}}$ Output $\mathrm{IOH}_{\mathrm{OH}} / \mathrm{I}_{\mathrm{OL}}$ |
| $\mathrm{I}_{0-1} \mathrm{I}_{3 \mathrm{a}}$ | Side A Data Inputs | 1.0/1.0 | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\mathrm{I}_{0-1} \mathrm{l}_{3 \mathrm{~b}}$ | Side B Data Inputs | 1.0/1.0 | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\mathrm{S}_{0}-\mathrm{S}_{1}$ | Common Select Inputs | 1.0/1.0 | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\bar{E}_{\text {a }}$ | Side A Enable Input (Active LOW) | 1.0/1.0 | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\bar{E}_{\text {b }}$ | Side B Enable Input (Active LOW) | 1.0/1.0 | $20 \mu \mathrm{~A} /-0.6 \mathrm{~mA}$ |
| $\bar{Z}_{\mathrm{a}}, \overline{\mathrm{Z}}_{\mathrm{b}}$ | Multiplexer Outputs (Inverted) | 50/33.3 | -1 mA/20 mA |

[^0]
## Functional Description

The 'F352 is a dual 4-input multiplexer. It selects two bits of data from up to four sources under the control of the common Select inputs ( $\mathrm{S}_{0}, \mathrm{~S}_{1}$ ). The two 4 -input multiplexer circuits have individual active LOW Enables ( $\bar{E}_{a}, \bar{E}_{b}$ ) which can be used to strobe the outputs independently. When the Enables ( $\overline{\mathrm{E}}_{\mathrm{a}}, \overline{\mathrm{E}}_{\mathrm{b}}$ ) are HIGH, the corresponding outputs ( $\overline{\mathrm{Z}}_{\mathrm{a}}, \overline{\mathrm{Z}}_{\mathrm{b}}$ ) are forced HIGH

The logic equations for the outputs are shown below:

$$
\begin{array}{r}
\overline{\mathrm{Z}}_{\mathrm{a}}=\overline{\mathrm{E}}_{\mathrm{a}} \bullet\left(\mathrm{I}_{0 \mathrm{a}} \bullet \overline{\mathrm{~S}}_{1} \bullet \overline{\mathrm{~S}}_{0}+\mathrm{I}_{1 \mathrm{a}} \bullet \overline{\mathrm{~S}}_{1} \bullet \mathrm{~S}_{0}+\right. \\
\left.\mathrm{I}_{2 \mathrm{a}} \bullet \mathrm{~S}_{1} \bullet \mathrm{~S}_{0}+\mathrm{I}_{3 \mathrm{a}} \bullet \mathrm{~S}_{1} \bullet \mathrm{~S}_{0}\right) \\
\overline{\mathrm{Z}}_{\mathrm{b}}=\overline{\mathrm{E}}_{\mathrm{b}} \bullet\left(\mathrm{I}_{0 \mathrm{~b}} \bullet \overline{\mathrm{~S}}_{1} \bullet \overline{\mathrm{~S}}_{0}+\mathrm{I}_{1 \mathrm{~b}} \bullet \overline{\mathrm{~S}}_{1} \bullet \mathrm{~S}_{0}+\right. \\
\left.\mathrm{I}_{2 \mathrm{~b}} \bullet \mathrm{~S}_{1} \bullet \mathrm{~S}_{0}+\mathrm{I}_{3 \mathrm{~b}} \bullet \mathrm{~S}_{1} \bullet \mathrm{~S}_{0}\right)
\end{array}
$$

## Truth Table

| Select Inputs |  | Inputs (a or b) |  |  |  |  | Output |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{S}_{0}$ | $S_{1}$ | $\overline{\mathbf{E}}$ | $\mathrm{I}_{0}$ | $I_{1}$ | $\mathrm{I}_{2}$ | $\mathrm{I}_{3}$ | $\overline{\mathbf{Z}}$ |
| X | X | H | X | X | X | $X$ | H |
| L | L | L | L | X | X | X | H |
| L | L | L | H | X | X | X | L |
| H | L | L | X | L | X | X | H |
| H | L | L | $X$ | H | X | $X$ | L |
| L | H | L | $X$ | X | L | $X$ | H |
| L | H | L | $X$ | X | H | X | L |
| H | H | L | X | X | X | L | H |
| H | H | L | X | X | X | H | L |

H $=$ HIGH Voltage Level
L = LOW Voltage Level
$\mathrm{X}=$ Immaterial

## Logic Diagram



| Absolute Maximum Ratings (Note 1) |  |
| :---: | :---: |
| Storage Temperature | $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ |
| Ambient Temperature under Bias | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |
| Junction Temperature under Bias Plastic | $\begin{aligned} & -55^{\circ} \mathrm{C} \text { to }+175^{\circ} \mathrm{C} \\ & -55^{\circ} \mathrm{C} \text { to }+150^{\circ} \mathrm{C} \end{aligned}$ |
| $V_{C C}$ Pin Potential to Ground Pin | -0.5 V to +7.0 V |
| Input Voltage (Note 2) | -0.5 V to +7.0 V |
| Input Current (Note 2) | -30 mA to +5.0 mA |
| Voltage Applied to Output in HIGH State (with $\mathrm{V}_{\mathrm{CC}}=0 \mathrm{~V}$ ) Standard Output TRI-STATE® Output | $\begin{gathered} -0.5 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{CC}} \\ -0.5 \mathrm{~V} \text { to }+5.5 \mathrm{~V} \end{gathered}$ |
| Current Applied to Output in LOW State (Max) | twice the rated lol (mA) |
| Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied. |  |
| Note 2: Either voltage limit or current limit is | sufficient to protect inputs. |

## Recommended Operating Conditions

Free Air Ambient Temperature

| Commercial | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ |
| :--- | ---: |
| Supply Voltage <br> Commercial | +4.5 V to +5.5 V |

## DC Electrical Characteristics

| Symbol | Parameter | 74F |  |  | Units | $\mathrm{V}_{\mathrm{cc}}$ | Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max |  |  |  |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage | 2.0 |  |  | V |  | Recognized as a HIGH Signal |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage |  |  | 0.8 | V |  | Recognized as a LOW Signal |
| $\mathrm{V}_{\mathrm{CD}}$ | Input Clamp Diode Voltage |  |  | -1.2 | V | Min | $\mathrm{I}_{\mathrm{IN}}=-18 \mathrm{~mA}$ |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH $74 \mathrm{~F} 10 \% \mathrm{~V}_{\mathrm{CC}}$ <br> Voltage $74 \mathrm{~F} 5 \% \mathrm{VCC}_{\mathrm{CC}}$ | $\begin{aligned} & 2.5 \\ & 2.7 \\ & \hline \end{aligned}$ |  |  | V | Min | $\begin{aligned} & \mathrm{I}_{\mathrm{OH}}=-1 \mathrm{~mA} \\ & \mathrm{I}_{\mathrm{OH}}=-1 \mathrm{~mA} \end{aligned}$ |
| $\mathrm{V}_{\mathrm{OL}}$ | Output LOW Voltage |  |  | 0.5 | V | Min | $\mathrm{l} \mathrm{OL}=20 \mathrm{~mA}$ |
| $\mathrm{I}_{\mathrm{H}}$ | Input HIGH 74F Current |  |  | 5.0 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=2.7 \mathrm{~V}$ |
| $\mathrm{I}_{\mathrm{BVI}}$ | Input HIGH Current 74F Breakdown Test |  |  | 7.0 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=7.0 \mathrm{~V}$ |
| $I_{\text {CEX }}$ | Output HIGH <br> Leakage Current 74F |  |  | 50 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=\mathrm{V}_{\text {CC }}$ |
| $\mathrm{V}_{\text {ID }}$ | Input Leakage $\quad 74 F$ Test | 4.75 |  |  | V | 0.0 | $\mathrm{I}_{\mathrm{ID}}=1.9 \mu \mathrm{~A}$ <br> All Other Pins Grounded |
| IOD | Output Leakage Circuit Current $\quad$ 74F |  |  | 3.75 | $\mu \mathrm{A}$ | 0.0 | $V_{I O D}=150 \mathrm{mV}$ <br> All Other Pins Grounded |
| $\mathrm{I}_{\mathrm{IL}}$ | Input LOW Current |  |  | -0.6 | mA | Max | $\mathrm{V}_{\text {IN }}=0.5 \mathrm{~V}$ |
| los | Output Short-Circuit Current | -60 |  | -150 | mA | Max | $\mathrm{V}_{\text {OUT }}=0 \mathrm{~V}$ |
| $\mathrm{I}_{\mathrm{CCH}}$ | Power Supply Current |  | 9.3 | 14 | mA | Max | $\mathrm{V}_{\mathrm{O}}=$ HIGH |
| $\mathrm{I}_{\text {CCL }}$ | Power Supply Current |  | 13.3 | 20 | mA | Max | $\mathrm{V}_{\mathrm{O}}=$ LOW |

## AC Electrical Characteristics

| Symbol | Parameter | 74F |  |  | 74F |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=+5.0 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \\ \hline \end{gathered}$ |  |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}, \mathrm{~V}_{\mathrm{CC}}=\mathrm{Com} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ |  |  |
|  |  | Min | Typ | Max | Min | Max |  |
| $\begin{aligned} & \mathrm{t}_{\mathrm{PLH}} \\ & \mathrm{t}_{\mathrm{PHL}} \\ & \hline \end{aligned}$ | Propagation Delay $S_{n}$ to $\bar{Z}_{n}$ | $\begin{aligned} & 4.0 \\ & 3.5 \\ & \hline \end{aligned}$ | $\begin{array}{r} 8.0 \\ 6.5 \\ \hline \end{array}$ | $\begin{gathered} 11.0 \\ 8.5 \\ \hline \end{gathered}$ | $\begin{aligned} & 3.5 \\ & 3.0 \\ & \hline \end{aligned}$ | $\begin{gathered} 12.5 \\ 9.5 \\ \hline \end{gathered}$ | ns |
| $\begin{aligned} & \mathrm{t}_{\mathrm{PLH}} \\ & \mathrm{t}_{\mathrm{PHL}} \end{aligned}$ | Propagation Delay $\bar{E}_{n}$ to $\bar{Z}_{n}$ | $\begin{aligned} & 3.0 \\ & 3.0 \\ & \hline \end{aligned}$ | $\begin{aligned} & 4.5 \\ & 5.0 \end{aligned}$ | $\begin{aligned} & 6.0 \\ & 7.0 \\ & \hline \end{aligned}$ | $\begin{aligned} & 2.5 \\ & 2.5 \\ & \hline \end{aligned}$ | $\begin{aligned} & 7.0 \\ & 8.0 \\ & \hline \end{aligned}$ | ns |
| $\begin{aligned} & \mathrm{t}_{\mathrm{PLH}} \\ & \mathrm{t}_{\mathrm{PHL}} \end{aligned}$ | Propagation Delay $I_{n}$ to $\bar{Z}_{n}$ | $\begin{aligned} & 2.0 \\ & 1.3 \end{aligned}$ | 5.2 2.5 | 7.0 4.0 | $\begin{aligned} & 2.0 \\ & 1.0 \end{aligned}$ |  | ns |

## Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:
 SJ = Small Outline SOIC EIAJ


Physical Dimensions inches (millimeters) (Continued)


## LIFE SUPPORT POLICY

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